



**FAST CMOS OCTAL
BUFFER/LINE DRIVER**

IDT74FCT540AT/CT

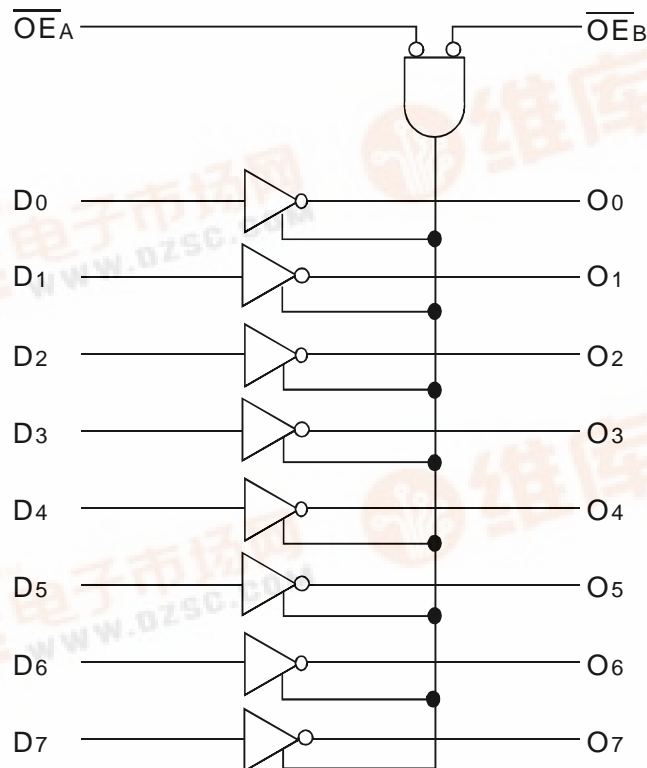
FEATURES:

- Low input and output leakage $\leq 1\mu\text{A}$ (max.)
- CMOS power levels
- True TTL input and output compatibility
 - $V_{OH} = 3.3\text{V}$ (typ.)
 - $V_{OL} = 0.3\text{V}$ (typ.)
- Meets or exceeds JEDEC standard 18 specifications
- A and C speed grades
- High drive outputs (-15mA I_{OH} , 64mA I_{OL})
- Power off disable outputs permit "live insertion"
- Available in SOIC, SSOP, and QSOP packages

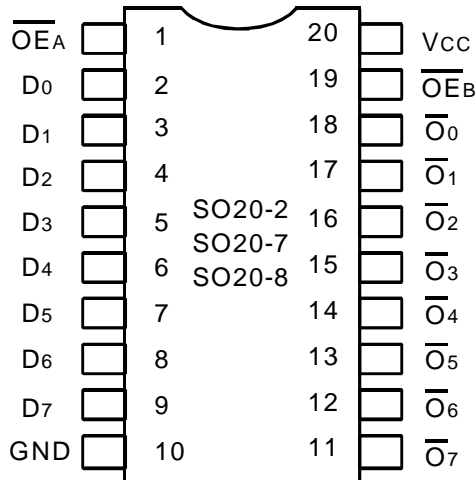
DESCRIPTION:

The IDT octal buffer/line driver is built using an advanced dual metal CMOS technology. The FCT540T is similar in function to the FCT240T, except that the inputs and outputs are on opposite sides of the package. This pinout arrangement makes these devices especially useful as output ports for microprocessors and as backplane drivers, allowing ease of layout and greater board density.

FUNCTIONAL BLOCK DIAGRAM



PIN CONFIGURATION



SOIC/ SSOP/ QSOP
TOP VIEW

ABSOLUTE MAXIMUM RATINGS(1)

Symbol	Rating	Max.	Unit
V _{TERM} ⁽²⁾	Terminal Voltage with Respect to GND	-0.5 to +7	V
V _{TERM} ⁽³⁾	Terminal Voltage with Respect to GND	-0.5 to V _{CC} +0.5	V
T _{STG}	Storage Temperature	-65 to +150	°C
I _{OUT}	DC Output Current	-60 to +120	mA

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NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability. No terminal voltage may exceed V_{CC} by +0.5V unless otherwise noted.
- Inputs and V_{CC} terminals only.
- Outputs and I/O terminals only.

CAPACITANCE (T_A = +25°C, f = 1.0MHz)

Symbol	Parameter ⁽¹⁾	Conditions	Typ.	Max.	Unit
C _{IN}	Input Capacitance	V _{IN} = 0V	6	10	pF
C _{OUT}	Output Capacitance	V _{OUT} = 0V	8	12	pF

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NOTE:

- This parameter is measured at characterization but not tested.

PIN DESCRIPTION

Pin Names	Description
\overline{OE}_A , \overline{OE}_B	3-State Output Enable Inputs (Active LOW)
D _x	Inputs
\overline{O}_x	Outputs

FUNCTION TABLE (1)

Inputs			Outputs
\overline{OE}_A	\overline{OE}_B	D	
L	L	L	H
L	L	H	L
H	H	X	Z

NOTE:

- H = HIGH Voltage Level
L = LOW Voltage Level
X = Don't Care
Z = High-Impedance

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Industrial: TA = -40°C to +85°C, VCC = 5.0V ± 5%

Symbol	Parameter	Test Conditions ⁽¹⁾	Min.	Typ. ⁽²⁾	Max.	Unit
V _{IH}	Input HIGH Level	Guaranteed Logic HIGH Level	2	—	—	V
V _{IL}	Input LOW Level	Guaranteed Logic LOW Level	—	—	0.8	V
I _{IH}	Input HIGH Current ⁽⁴⁾	V _{CC} = Max. V _I = 2.7V	—	—	±1	μA
I _{IL}	Input LOW Current ⁽⁴⁾		V _I = 0.5V	—	—	
I _{OZH}	High Impedance Output Current (3-State output pins) ⁽⁴⁾	V _{CC} = Max. V _O = 2.7V	—	—	±1	μA
I _{OZL}			V _O = 0.5V	—	—	
I _I	Input HIGH Current ⁽⁴⁾	V _{CC} = Max., V _I = V _{CC} (Max.)	—	—	±1	μA
V _{IK}	Clamp Diode Voltage	V _{CC} = Min., I _{IN} = -18mA	—	-0.7	-1.2	V
V _H	Input Hysteresis	—	—	200	—	mV
I _{CC}	Quiescent Power Supply Current	V _{CC} = Max., V _{IN} = GND or V _{CC}	—	0.01	1	mA

OUTPUT DRIVE CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾	Min.	Typ. ⁽²⁾	Max.	Unit
V _{OH}	Output HIGH Voltage	V _{CC} = Min. I _{OH} = -8mA	2.4	3.3	—	V
		V _{IN} = V _{IH} or V _{IL} I _{OH} = -15mA	2	3	—	
V _{OL}	Output LOW Voltage	V _{CC} = Min. V _{IN} = V _{IH} or V _{IL} I _{OL} = 64mA	—	0.3	0.55	V
I _{OS}	Short Circuit Current	V _{CC} = Max, V _O = GND ⁽³⁾	-60	-120	-225	mA

NOTES:

1. For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical values are at V_{CC} = 5.0V, +25°C ambient.
3. Not more than one output should be shorted at one time. Duration of the short circuit test should not exceed one second.
4. The test limit for this parameter is ±5μA at TA = -55°C.

POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
ΔI_{CC}	Quiescent Power Supply Current TTL Inputs HIGH	$V_{CC} = \text{Max.}$ $V_{IN} = 3.4V^{(3)}$		—	0.5	2	mA
I_{CCD}	Dynamic Power Supply Current ⁽⁴⁾	$V_{CC} = \text{Max.}$ Outputs Open $\overline{OE}_A = \overline{OE}_B = \text{GND}$ One Input Toggling 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	0.15	0.25	mA/ MHz
I_C	Total Power Supply Current ⁽⁶⁾	$V_{CC} = \text{Max.}$ Outputs Open $f_i = 10\text{MHz}$ 50% Duty Cycle $\overline{OE}_A = \overline{OE}_B = \text{GND}$ One Bit Toggling	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	1.5	3.5	mA
			$V_{IN} = 3.4$ $V_{IN} = \text{GND}$	—	1.8	4.5	
		$V_{CC} = \text{Max.}$ Outputs Open $f_i = 2.5\text{MHz}$ 50% Duty Cycle $\overline{OE}_A = \overline{OE}_B = \text{GND}$ Eight Bits Toggling	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	3	6 ⁽⁵⁾	
			$V_{IN} = 3.4$ $V_{IN} = \text{GND}$	—	5	14 ⁽⁵⁾	

NOTES:

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at $V_{CC} = 5.0V$, $+25^\circ\text{C}$ ambient.
- Per TTL driven input ($V_{IN} = 3.4V$). All other inputs at V_{CC} or GND.
- This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
- Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.
- $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$
 $I_C = I_{CC} + \Delta I_{CC} \cdot D_{HNT} + I_{CCD} \cdot (f_{CP}/2 + f_i N_i)$
 $I_{CC} = \text{Quiescent Current}$
 $\Delta I_{CC} = \text{Power Supply Current for a TTL High Input } (V_{IN} = 3.4V)$
 $D_{HNT} = \text{Duty Cycle for TTL Inputs High}$
 $N_T = \text{Number of TTL Inputs at } D_H$
 $I_{CCD} = \text{Dynamic Current Caused by an Input Transition Pair (HLH or LHL)}$
 $f_{CP} = \text{Clock Frequency for Register Devices (Zero for Non-Register Devices)}$
 $f_i = \text{Input Frequency}$
 $N_i = \text{Number of Inputs at } f_i$
 All currents are in milliamps and all frequencies are in megahertz.

SWITCHING CHARACTERISTICS OVER OPERATING RANGE

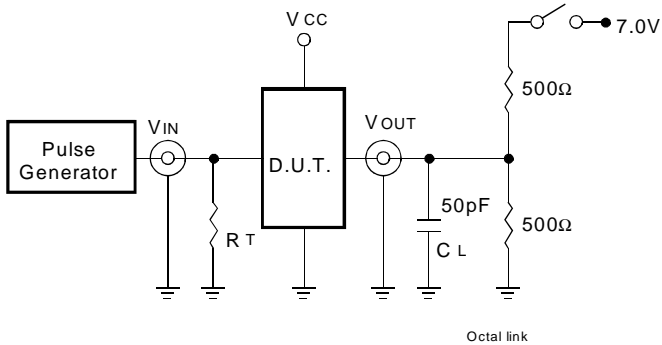
Symbol	Parameter	Condition ⁽¹⁾	FCT540AT		FCT540CT		Unit
			Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	
t_{PLH} t_{PHL}	Propagation Delay D_N to \overline{O}_N	$C_L = 50\text{pF}$ $R_L = 500\Omega$	1.5	4.8	1.5	4.3	ns
t_{PZH} t_{PZL}	Output Enable Time		1.5	6.2	1.5	5.8	ns
t_{PHZ} t_{PLZ}	Output Disable Time		1.5	5.6	1.5	5.2	ns

NOTES:

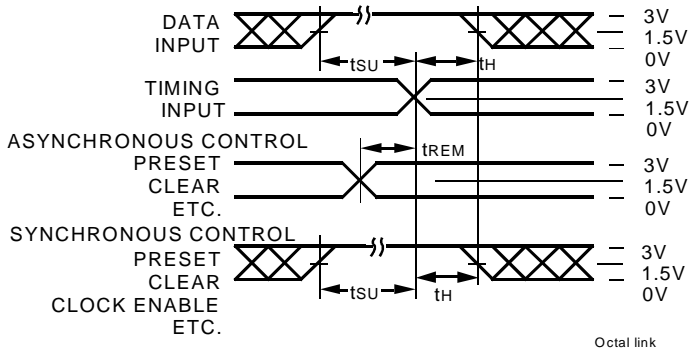
- See Test Circuit and Waveforms.
- Minimum limits are guaranteed but not tested on Propagation Delays.

TEST CIRCUITS AND WAVEFORMS

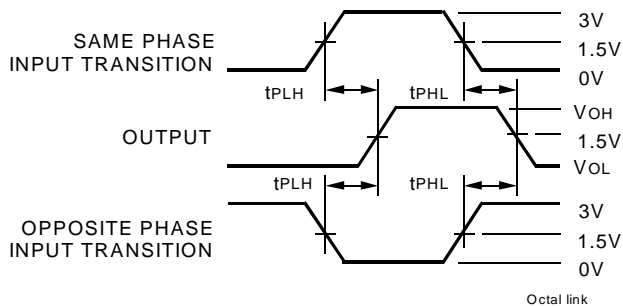
TEST CIRCUITS FOR ALL OUTPUTS



SET-UP, HOLD, AND RELEASE TIMES



PROPAGATION DELAY



SWITCH POSITION

Test	Switch
Open Drain	Closed
Disable Low	
Enable Low	
All Other Tests	Open

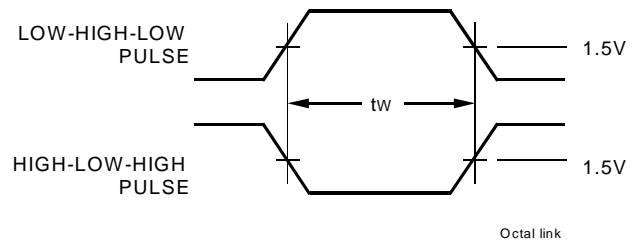
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DEFINITIONS:

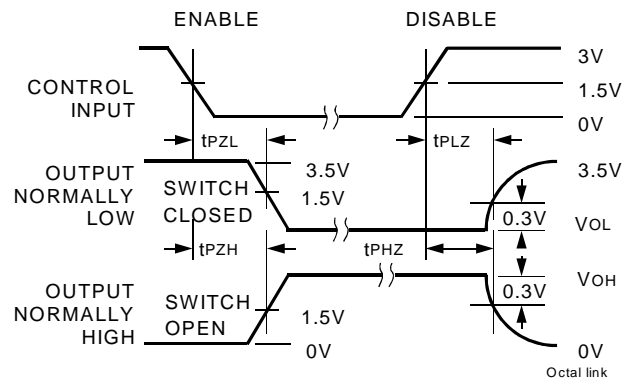
CL = Load capacitance: includes jig and probe capacitance.

RT = Termination resistance: should be equal to ZOUT of the Pulse Generator.

PULSE WIDTH



ENABLE AND DISABLE TIMES



NOTES:

1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH
2. Pulse Generator for All Pulses: Rate $\leq 1.0\text{MHz}$; $t_f \leq 2.5\text{ns}$; $t_r \leq 2.5\text{ns}$

ORDERING INFORMATION

IDT XX FCT X X

Temperature
Range

Device
Type

Package

SO Small Outline IC (SO20-2)
PY Shrink Small Outline Package (SO20-7)
Q Quarter-size Small Outline Package (SO20-8)

540AT Fast CMOS Octal Buffer/Line Driver
540CT

74 - 40°C to +85°C



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